

Search Notes



Application/Control No.

10/537,386

Examiner

Ahshik Kim

**Applicant(s)/Patent under
Reexamination**

RIED ET AL.

Art Unit

2876

SEARCHED

Class	Subclass	Date	Examiner
235	492	4/10/2007	AK
	451		
	488		
361	736		
	737		
343	866		
	873	V	cd

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)